

# Specification For UV Series

## HPL-H99IU1C0



### 1. Features

- Dimension : 9.0mm(L)×9.0mm(W)
- All Metal Design Cu Substrate/ Al reflector with Quartz Glass Lens
- Quartz-like silicon resin
- Good for SMT process
- Low thermal resistance
- The InGaN Chip inside

### 2. Application

- UV Printing/UV Curing
- Medical
- Electronics Assembly
- Opto Electronics
- Special Lighting
- Defect Detection

5F, No 173-8, Yung-Fon Road, Tu-Cheng District, New Taipei City, Taiwan, R.O.C.  
TEL: +886-2-8262-8886 FAX : +886-2-8262-8885

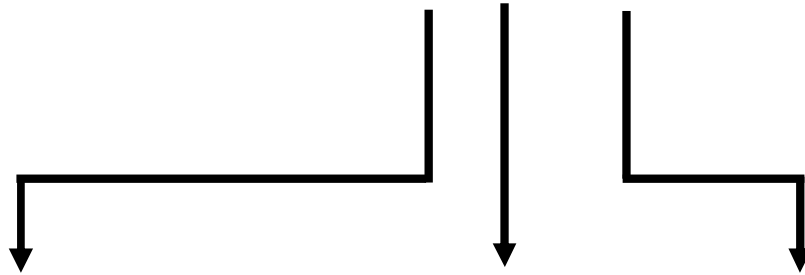


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General Information

**HPL - H99 X<sub>1</sub>X<sub>2</sub>1C0**



**X<sub>1</sub>:Lens & Assembly Type-**  
I : 70° Lens Emitter only  
J : 70°Lens Emitter on Standard Star

**X<sub>2</sub>:Color-**  
U: UV390~420nm

**Power-**  
C: 3W

## Part Number Matrix

Type Wavelength	70°Lens	70°Lens & Star
V	HPL-H99IU1C0	HPL-H99JU1C0

## Absolute Maximum Ratings

(T<sub>j</sub>=25°C)

Parameter	Symbol	Rating	Unit
Power Dissipation UV390-420nm	P	3	W
Forward Current	I <sub>F</sub>	700	mA
Forward Pulse Current (1/10 Duty Cycle, 400msec Pulse Width)	I <sub>FP</sub>	1000	mA
Thermal Resistance, Junction-Case	R <sub>th, J-C1</sub>	5	°C/W
LED Junction Temperature	T <sub>J</sub>	125	°C
Operating Temperature Range	T <sub>opr</sub>	- 40°C to + 80°C	
Storage Temperature Range	T <sub>stg</sub>	- 40°C to + 120°C	
Soldering Condition	T <sub>sol</sub>	260°C For 5 Seconds	

Note: 1. The thermal resistance value is measured with MCPCB (Star).

## Initial Electrical/Optical Characteristics

- Forward Voltage** (T<sub>j</sub>=25°C)

Wavelength	Forward Voltage					
	Symbol	MIN.	TYP.	MAX.	Test Condition	Unit
390~420nm	V <sub>F</sub>	3.03	3.8	4.47	I <sub>F</sub> = 700mA	V

**Caution:** The real output is decided by chip capability

- Radiant Flux**(T<sub>j</sub>=25°C)

Wavelength	Radiant Flux					
	Symbol	MIN.	TYP.	MAX.	Test Condition	Unit
410~420nm	Φ <sub>e</sub>	500	850	-	I <sub>F</sub> = 700mA	mW
400~410nm		500	850	-		
390~400nm		500	850	-		

**Caution:** The real output is decided by chip capability

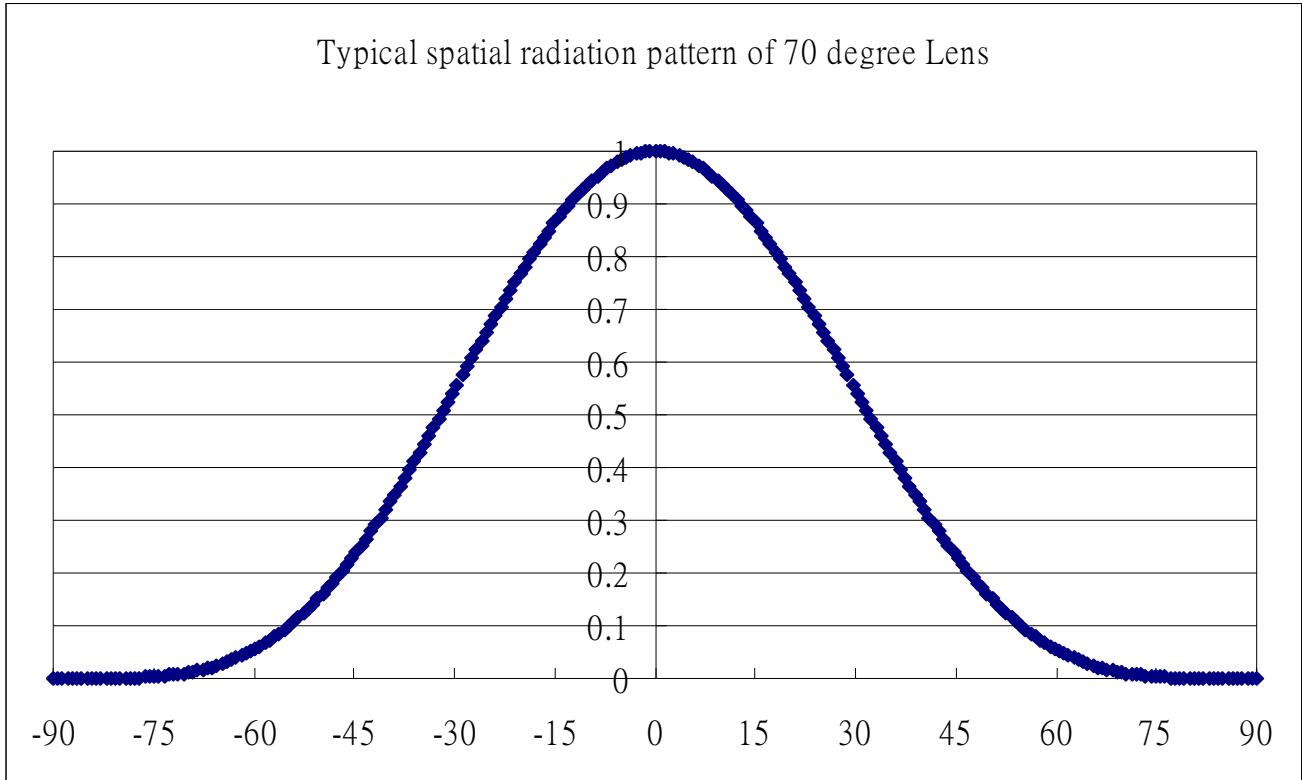
- Peak wavelength** (T<sub>j</sub>=25°C)

Wavelength	Wavelength					
	Symbol	MIN.	TYP.	MAX.	Test Condition	Unit
390~420nm	λ <sub>p</sub>	390	-	420	I <sub>F</sub> = 700mA	nm

- Spectra half-width** (T<sub>j</sub>=25°C)

Wavelength	Wavelength					
	Symbol	MIN.	TYP.	MAX.	Test Condition	Unit
390~420nm	Δλ	-	15	-	I <sub>F</sub> = 700mA	nm

- **Typical Radiation Pattern**



**Fig. (70° Lens) Typical Representative Spatial Radiation Pattern**

● Bin Code List for Reference

(T<sub>j</sub>=25°C)

Item	Bin Code	Symbol	Condition	Min.	Max.	Unit
Forward Voltage <sup>1</sup>	H	V <sub>F</sub>	I <sub>F</sub> = 700 [mA]	3.03	3.27	V
	J			3.27	3.51	
	K			3.51	3.75	
	L			3.75	3.99	
	M			3.99	4.23	
	N			4.23	4.47	
Radiant Flux <sup>2</sup>	D	Φ <sub>e</sub>	I <sub>F</sub> = 700 [mA]	350	425	mW
	E			425	500	
	F			500	600	
	G			600	700	
	H			700	800	
	J			800	900	

● Wavelength Bins

Wavelength <sup>3</sup>	Bin Code	Symbol	Condition	Min.	Max.	Unit
U 390~420nm	UF	λ <sub>p</sub>	I <sub>F</sub> = 700 [mA]	415	420	nm
	UE			410	415	
	UD			405	410	
	UC			400	405	
	UB			395	400	
	UA			390	395	

Note

1. Forward voltage measurement allowance is ± 0.1V.
2. Radiant flux measurement allowance is ± 10%.
3. Wavelength measurement allowance is ± 2nm.

## Characteristic Diagram

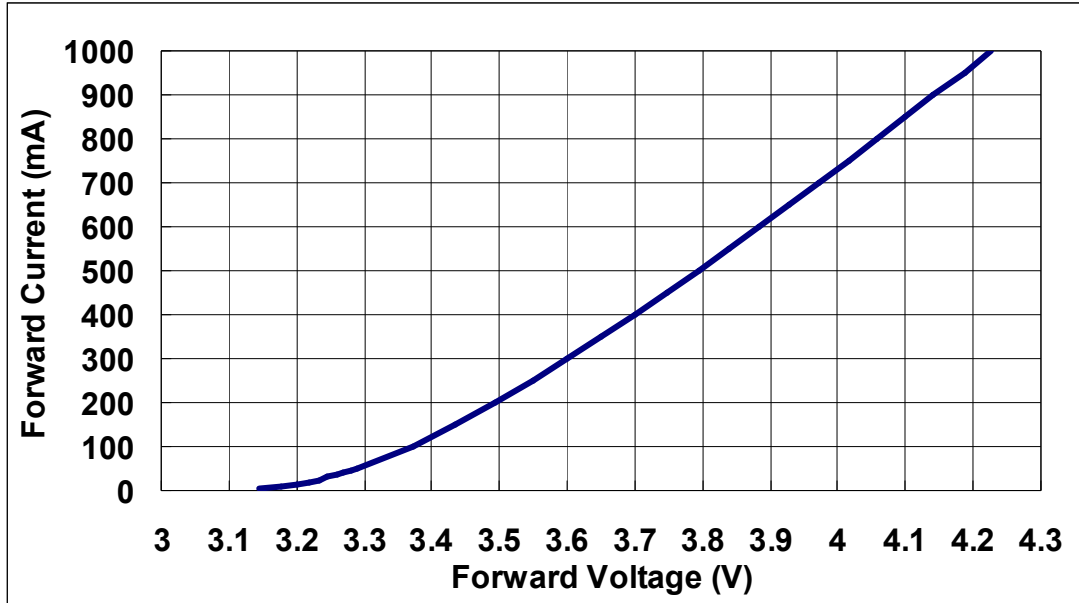


Fig. Forward Current vs. Forward Voltage

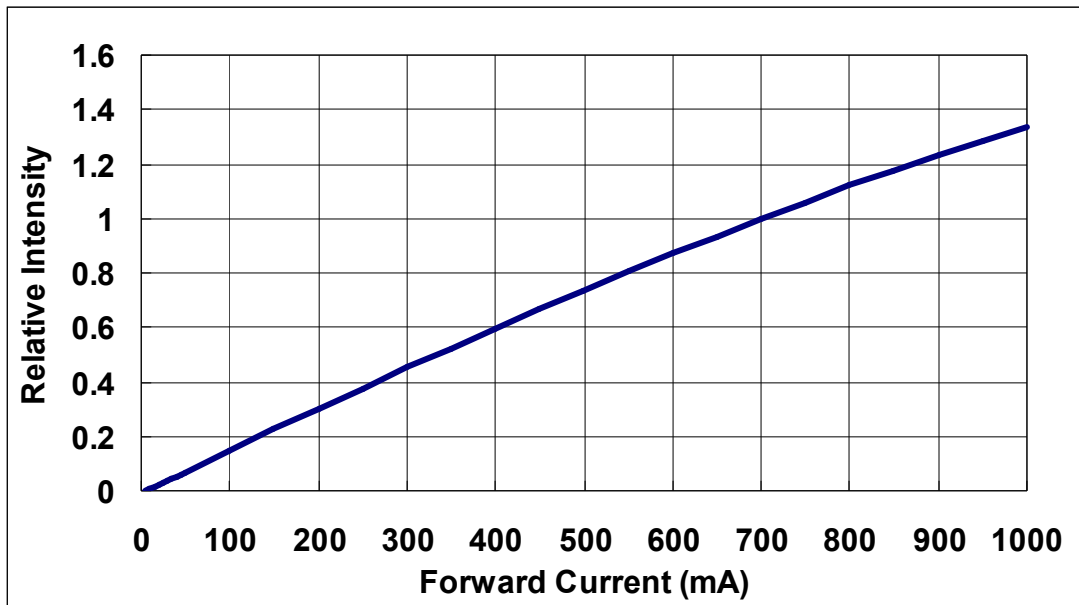


Fig. Relative Intensity vs. Forward Current.



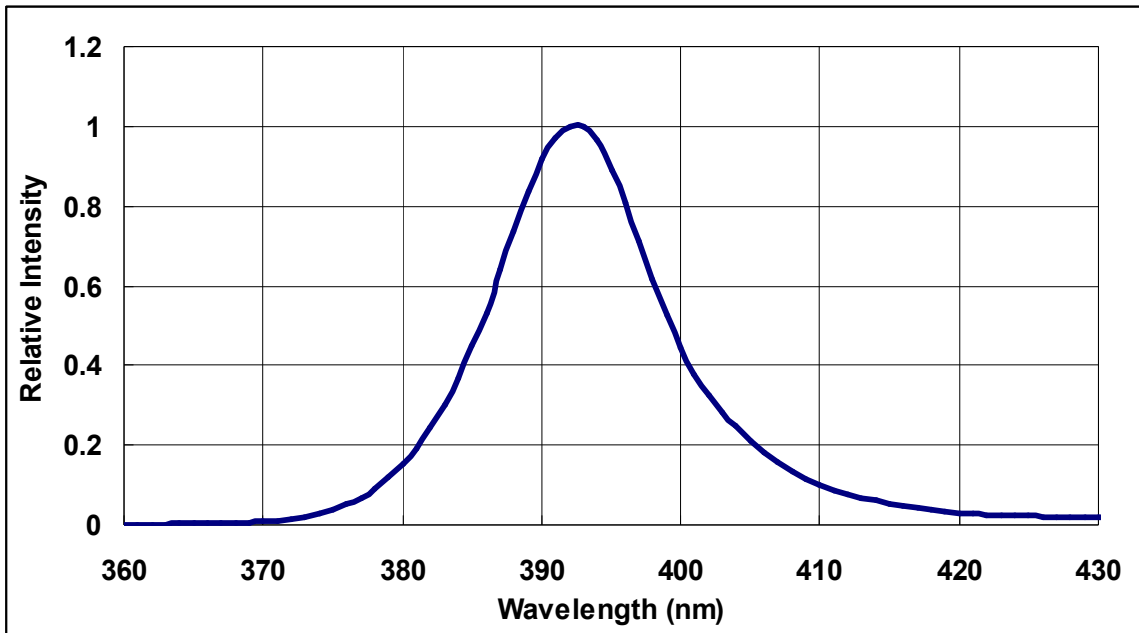


Fig. Typical Relative Intensity vs. wavelength

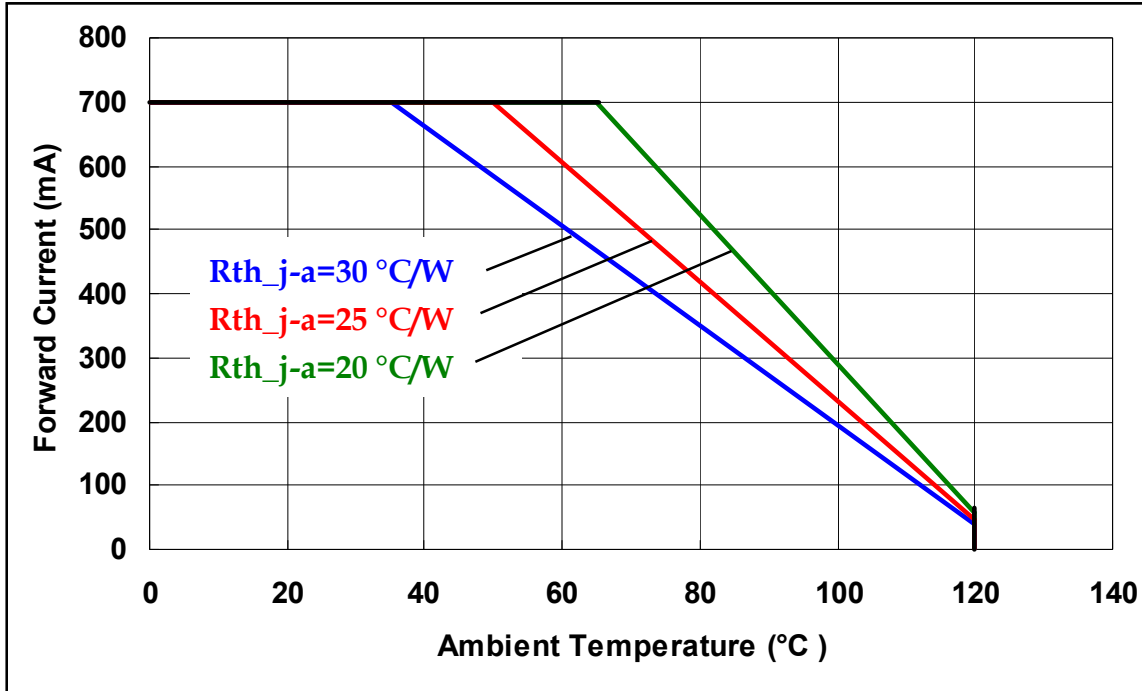


Fig. Forward Current Degrading Curve

Note:

$R_{th\_j-a}$  : junction to Ambient Thermal Resistance

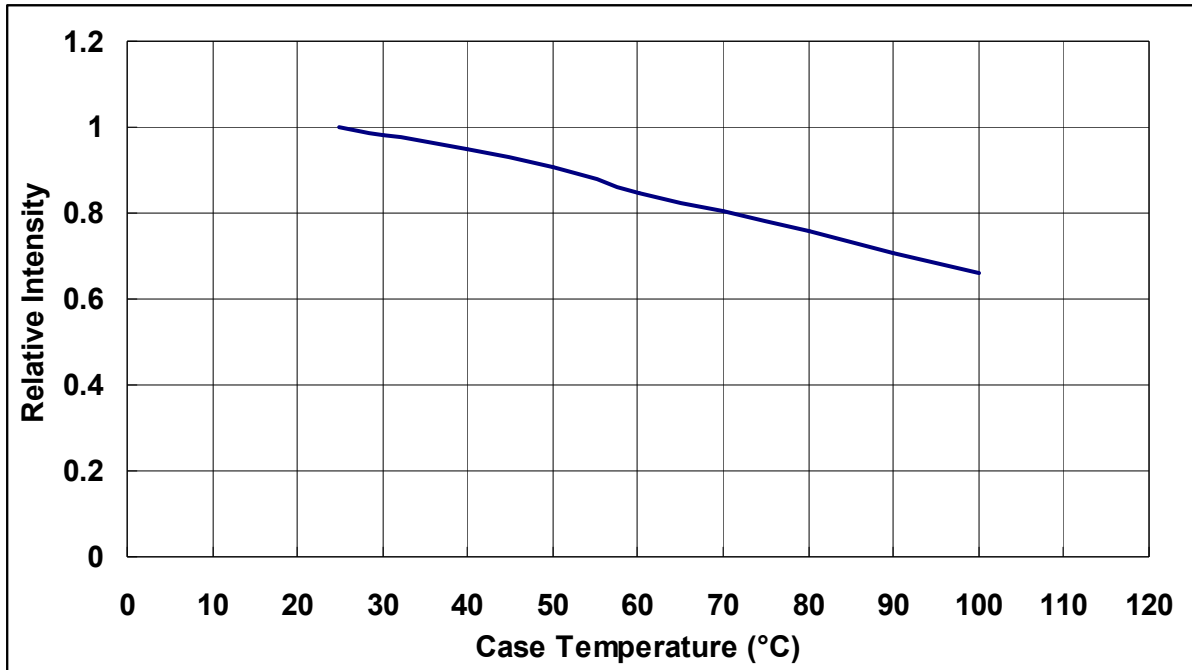


Fig. Relative Intensity vs. Case Temperature

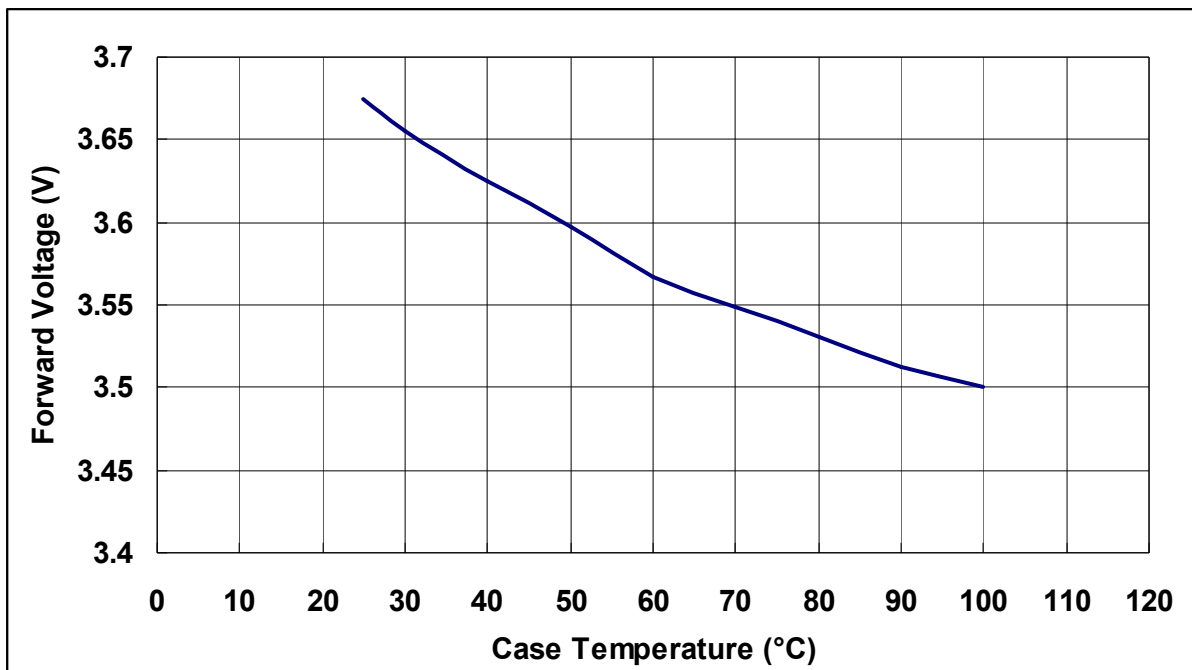


Fig. Forward Voltage vs. Case Temperature

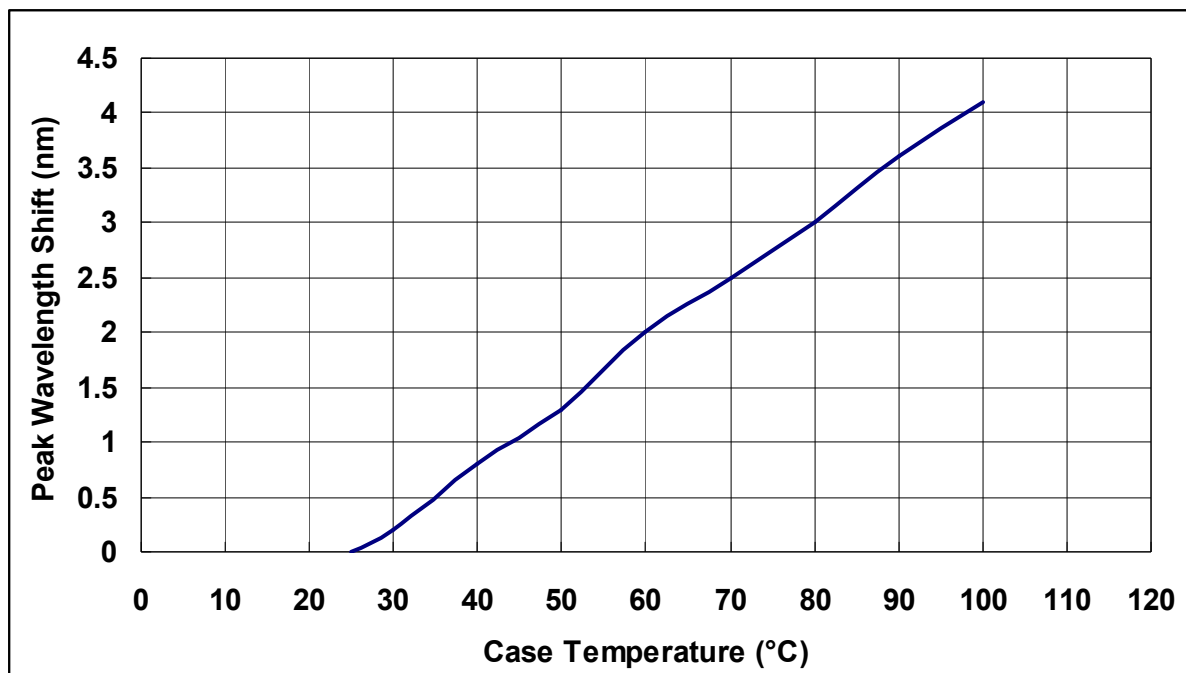
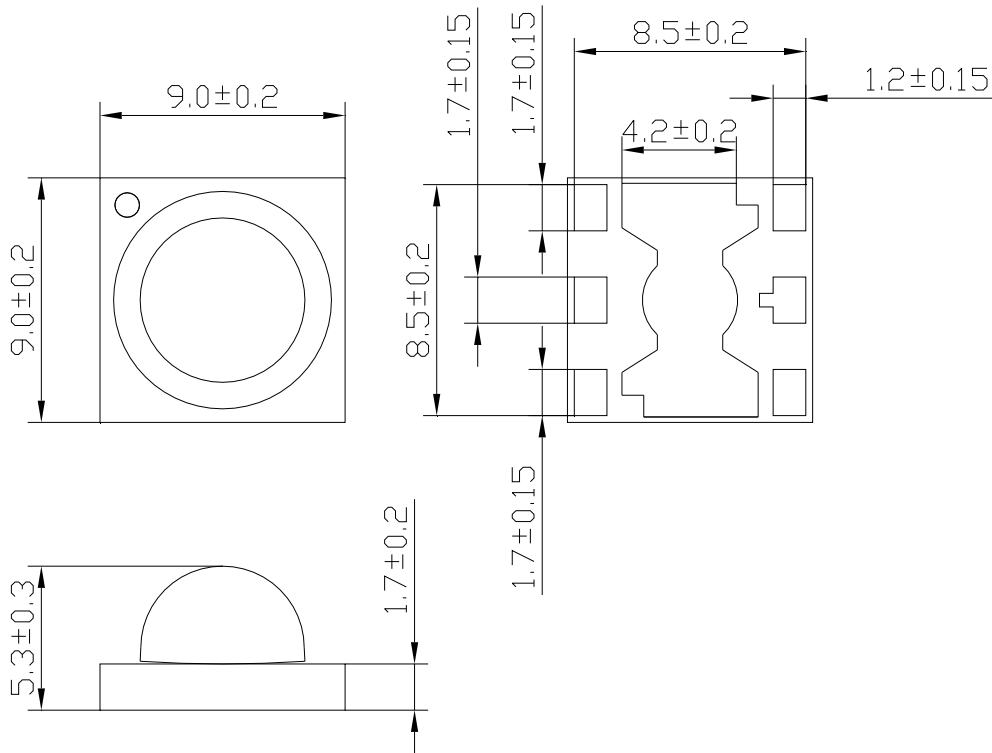


Fig. Peak Wavelength shift vs. Case Temperature

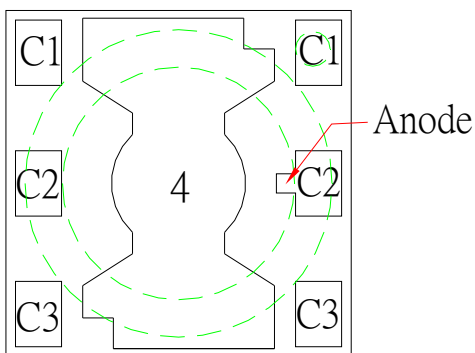
## Outline Dimension

### HPL-H99IU1C0

Unit : mm



### Pad Configuration

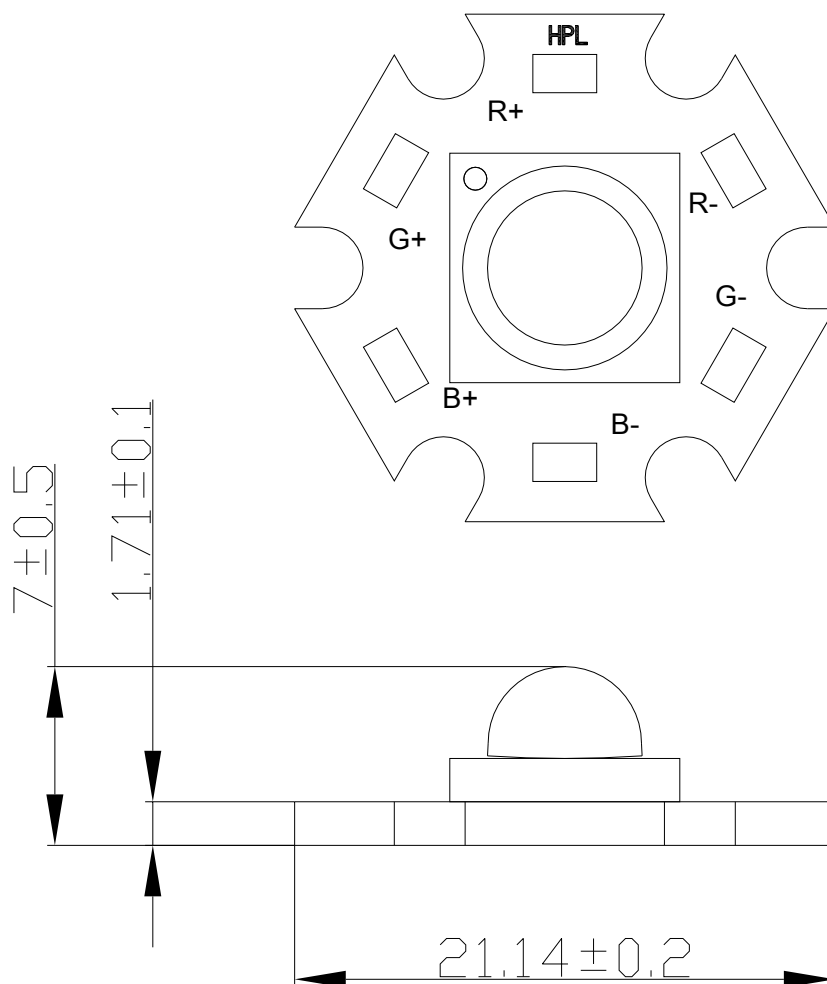


PAD	Function
C1	-
C2	Chip
C3	-
4	Thermal

Fig. Pad configuration.

Note : Thermal pad is not electrically neutral. Do not electrically connect either the anode or cathode to the Thermal pad.

### HPL-H99JU1C0



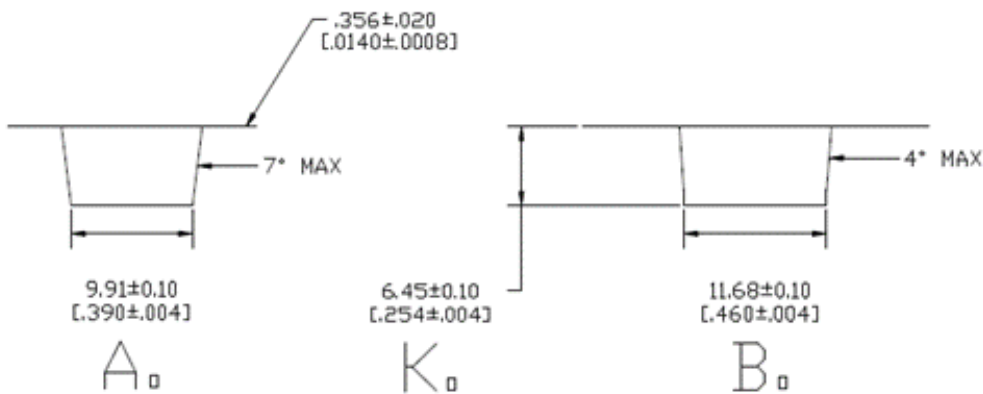
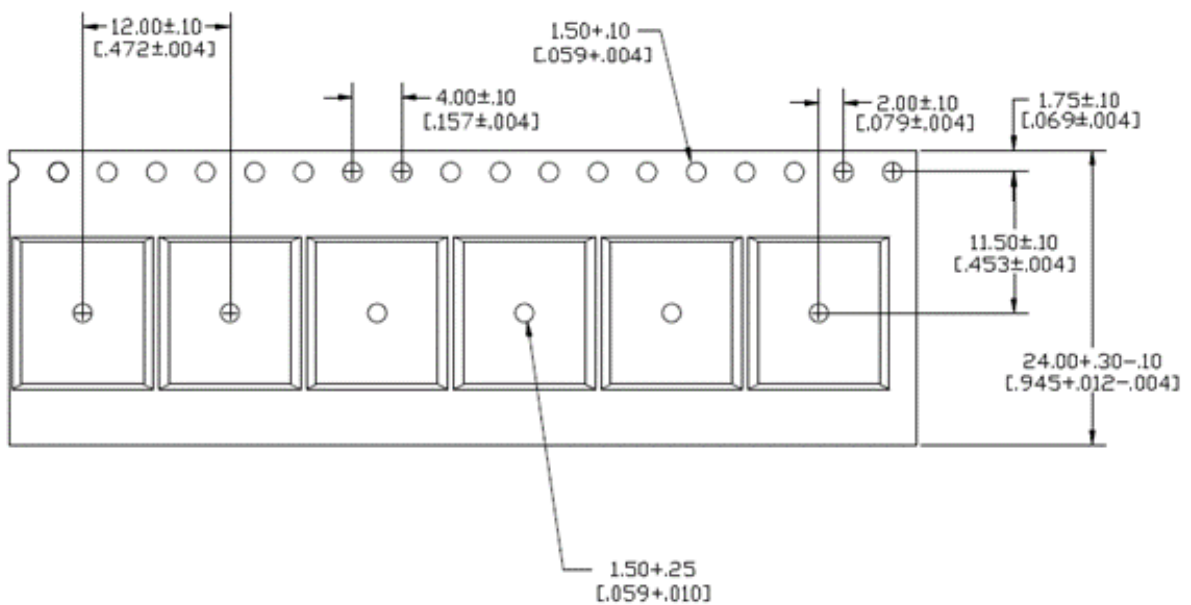
## Shipping Package Style

### Tapping Dimension Packaging Specification

#### 70 lens Type :

- Moisture proof bag.
- 1 Reel/bag.
- Q'ty: 200(MAX)/Reel.

Unit : mm



MM  
[INCH]

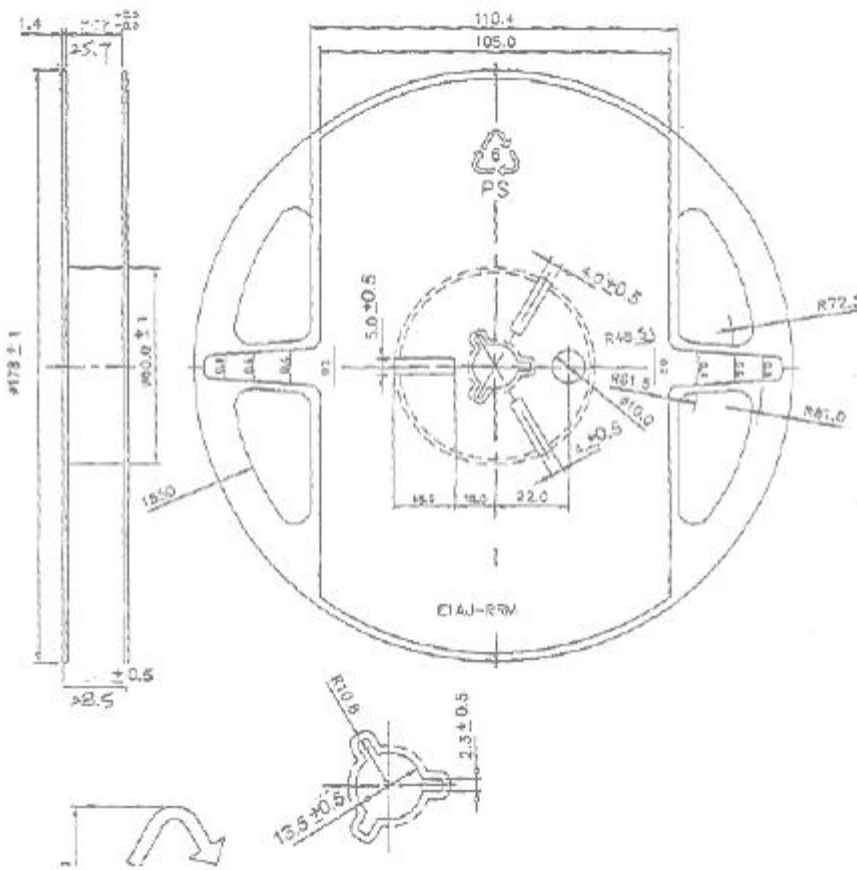
**Package**

Box Type	Dimension (mm)	Reel/Box	Lens Type (Pcs)
Small Box(S)	230x85x265	3 Reel/Box	600
Middle Box(M)	470x265x270	18 Reel/Box	3600
Large Box(L)	470x435x270	30 Reel/Box	6000

**Reel Packaging :**

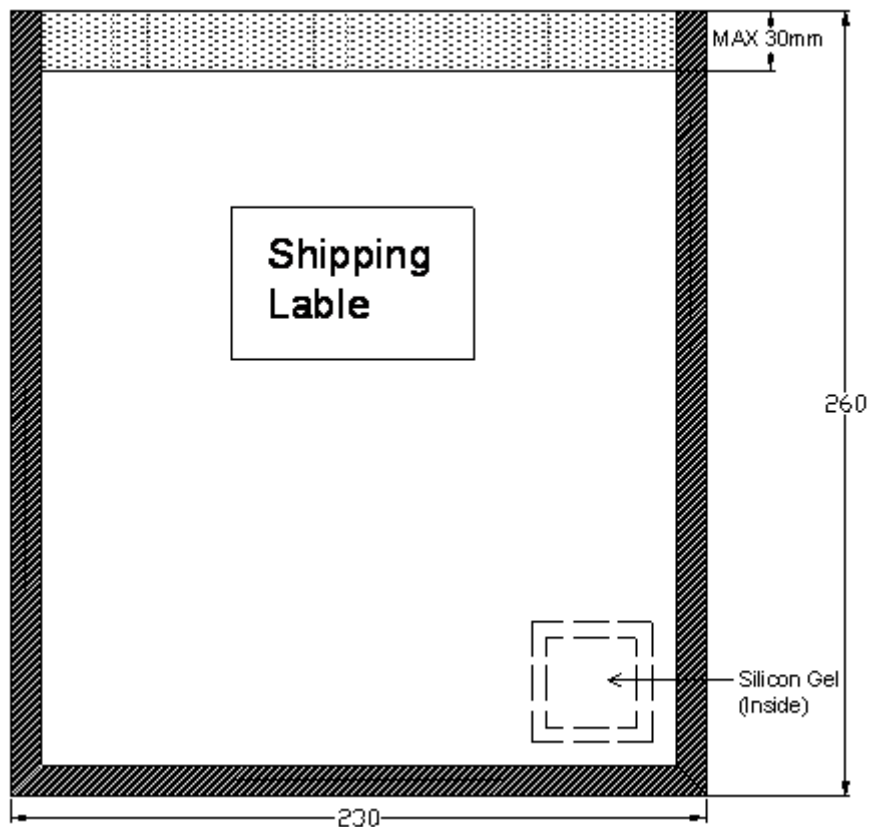
Reel Part :

Unit : mm



**Anti Statistic Bag :**

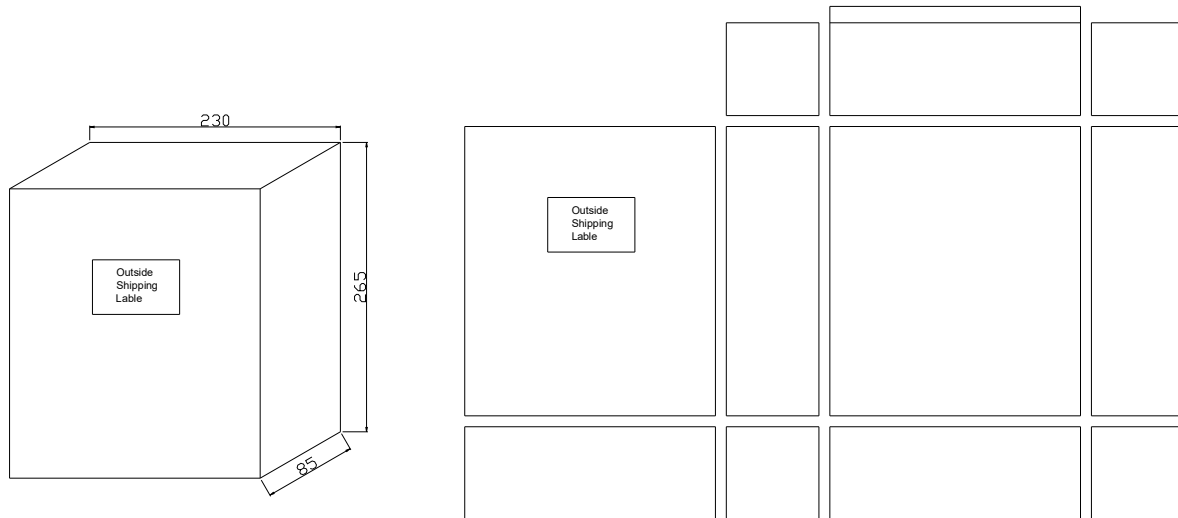
Unit : mm





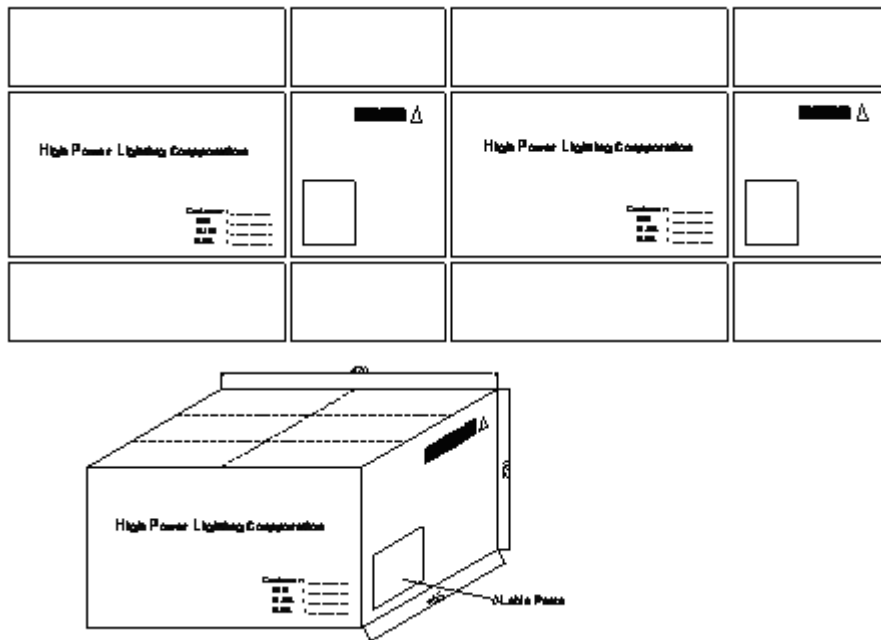
### Small Box

Unit : mm



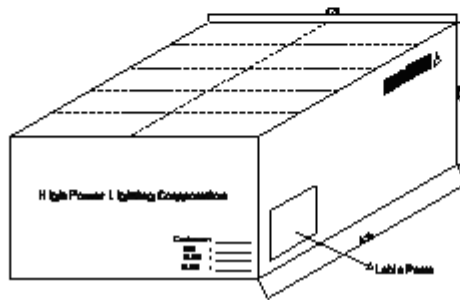
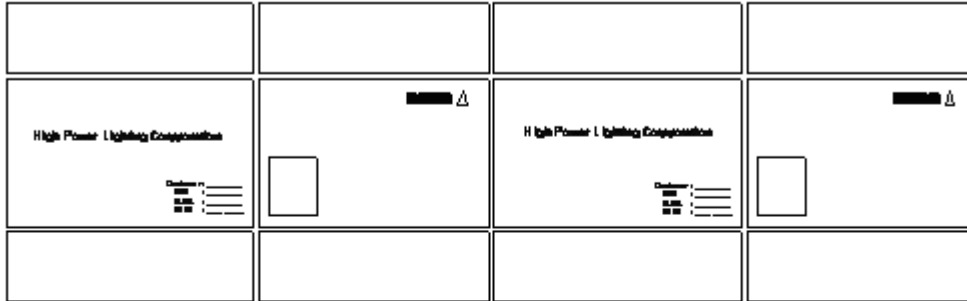
### Middle Box

Unit : mm



Large Box

Unit : mm



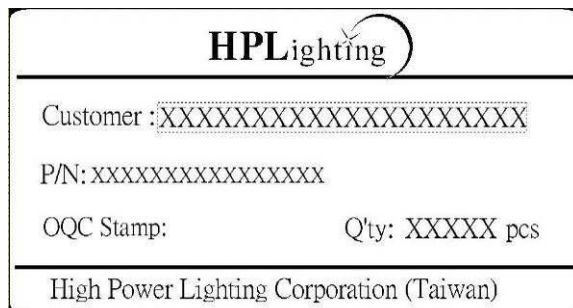
Label Formation

70mm

Unit : mm

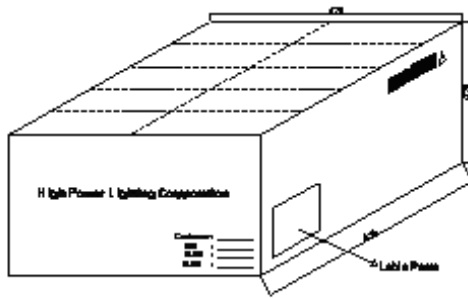
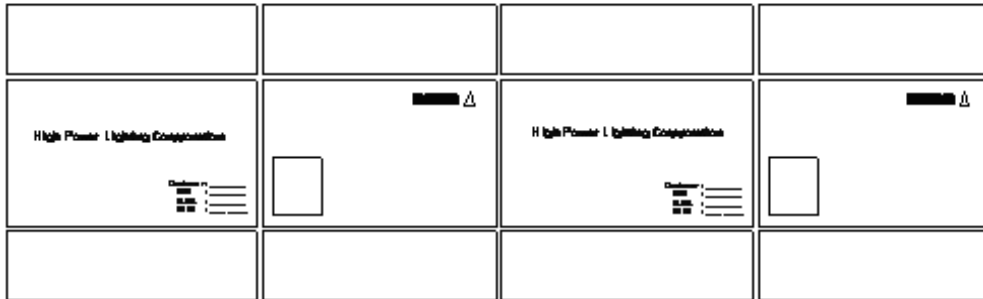


40mm



Package  
Large Box

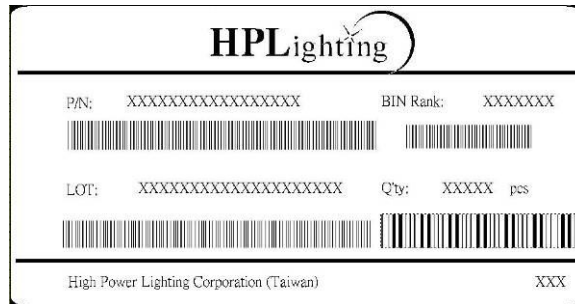
Unit : mm



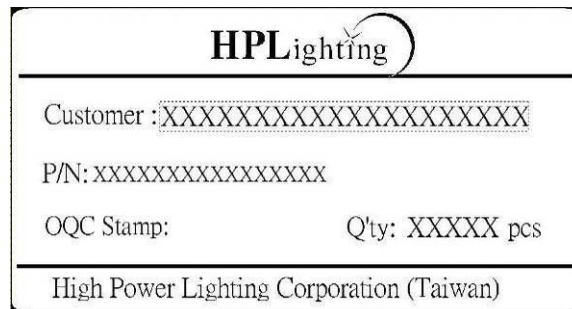
Label Formation

70mm

Unit : mm



40mm

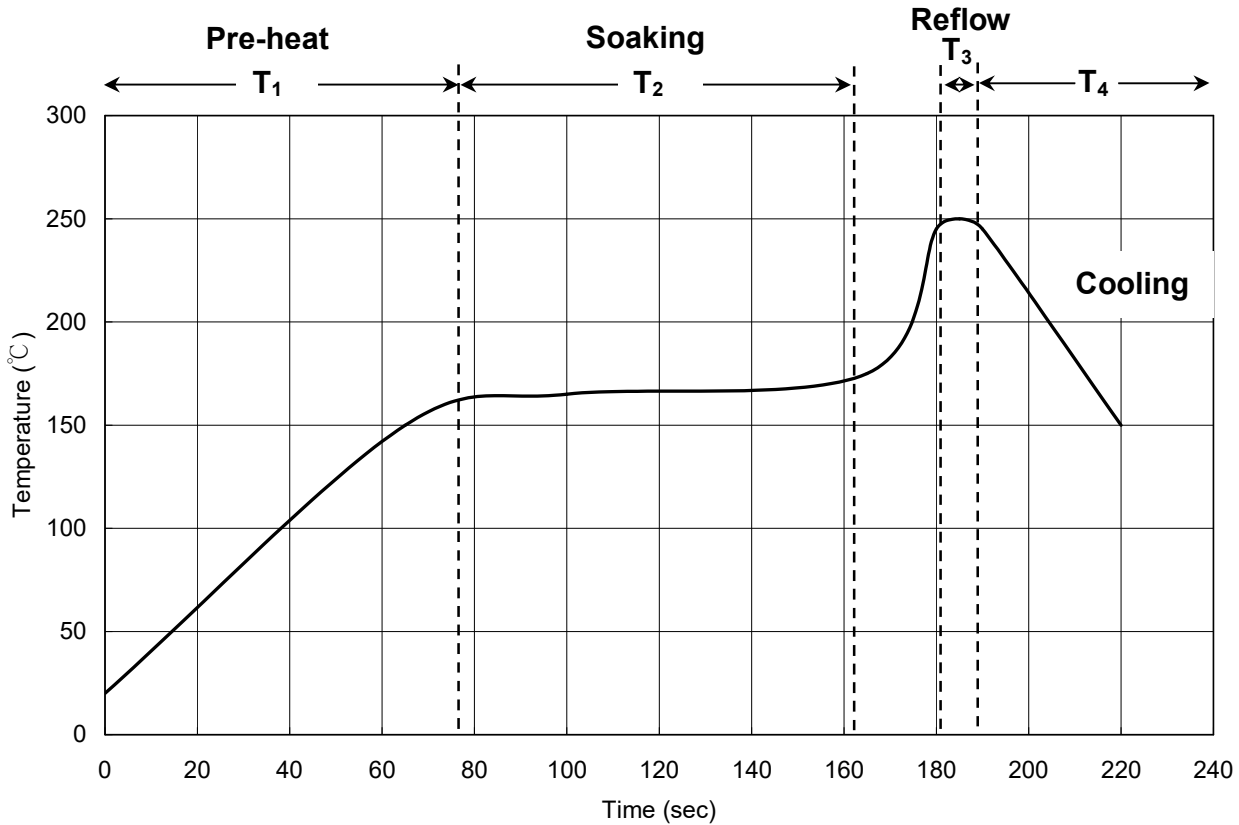


## Qualification Reliability Testing

Classification	Test Item	Test conditions	Reference Standard
Endurance Test	Operation Life	I <sub>F</sub> = 700mA Ta = 25°C Test Duration = 1000hrs	MIL-STD-750: 1026 MIL-STD-883: 1005 JIS C 7021: B-1
	High Temperature High Humidity Storage	IF = 700mA Ta = 85±5°C RH = 85±5% Test Duration = 1000hrs	MIL-STD-202: 103B JIS C 7021: B-11
	High Temperature Storage	Ta = 105±5°C Test Duration = 1000hrs	MIL-STD-202: 1008 JIS C 7021: B10
	Low Temperature Storage	Ta = -40±5°C Test Duration = 1000hrs	JIS C 7021: B-12
Environmental Test	Temperature Cycling	-40°C ~ 25°C ~ 105°C ~ 25°C 30min 5min 30min 5min Test Duration = 10 cycle	MIL-STD-202: 107D MIL-STD-750: 1051 MIL-STD-883: 1010 JIS C 7021: A-4
	Thermal Shock	-55±5°C ~ 105±5°C 30min 30min Test Duration = 10 cycle	MIL-STD-202: 107D MIL-STD-750: 1051 MIL-STD-883: 1011
	Solder Resistance	Tsol = 260±5°C Dwell Time = 10sec	MIL-STD-202: 210A MIL-STD-750: 2031 JIS C 7021: A-1
Measuring Items	Symbol	Measuring Conditions	Failure Criteria
Forward voltage	V <sub>F</sub>	IF =700mA	V <sub>F</sub> shift > 10%
Luminous	Iv%	IF =700mA	Iv% shift > 10%

## Recommended Solder Profile

Soldering Recommended soldering conditions:



T <sub>1</sub>	Ramp up rate	1.0 ~ 3.0 °C /sec
	Pre-heat time	50 ~ 80 sec
T <sub>2</sub>	Soaking temperature	155 ~ 185 °C
	Dwell time during soaking	60 ~ 120 sec
T <sub>3</sub>	Reflow temperature	240 ~ 250 °C
	Reflow time	Max 10 sec
	Ramp up rate during reflow	1.2 ~ 2.3 °C /sec
T <sub>4</sub>	Cooling	1.0 ~ 6.0 °C /sec

Note: Suggest using Sn96Ag3Cu0.5 lead free solder.

## Cleaning

Use alcohol-based cleaning solvents such as isopropyl alcohol to clean the LED if necessary.

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